Scanning Electron Microscopy and X-ray Microanalysis, 10.0 credits

Svepelektronmikroskopi och röntgenmikroanalys, 10.0 hp

Third-cycle education course

6FIEI45

Department of Management and Engineering

Valid from: Second half-year 2023

Approved by Head of Department	**Approved** 2022-10-07
Revised by Head of Department	**Revised** 2023-11-13
Registration number IEI-2023-00616	

Grading

Two-grade scale